

**Notice of References Cited**Application/Control No.  
09/447,351Applicant(s)/Patent Under  
Reexamination  
HUBERMAN ET AL.Examiner  
Van Kim T. NguyenArt Unit  
2661

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,222,843	04-2001	Mauger, Roy Harold	370/397
	B	US-6,496,508	12-2002	Breuckheimer et al.	370/397
	C	US-6,424,700	07-2002	Thibon et al.	379/32.04
	D	US-6,389,011	05-2002	Allen et al.	370/356
	E	US-6,356,627	03-2002	Hayball et al.	379/112.01
	F	US-6,351,521	02-2002	DuRee et al.	379/15.01
	G	US-5,956,334	09-1999	Chu et al.	370/395.2
	H	US-5,923,742	07-1999	Kodialam et al.	379/133
	I	US-5,832,064	11-1998	Jeong, Kwang-Tae	379/92.02
	J	US-6,310,950	10-2001	Spildener et al.	379/219
	K	US-5,596,576	01-1997	Milito, Rodolfo A.	370/450
	L	US-6,243,449	06-2001	Margulis et al.	379/112.04
	M	US-6,038,309	03-2000	Ram et al.	379/229

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.